

SPP2303

DESCRIPTION

The SPP2303 is the P-Channel logic enhancement mode power field effect transistors are produced using high cell density , DMOS trench technology.

This high density process is especially tailored to minimize on-state resistance.

These devices are particularly suited for low voltage application such as cellular phone and notebook computer power management and other battery powered circuits, and low in-line power loss are needed in a very small outline surface mount package.

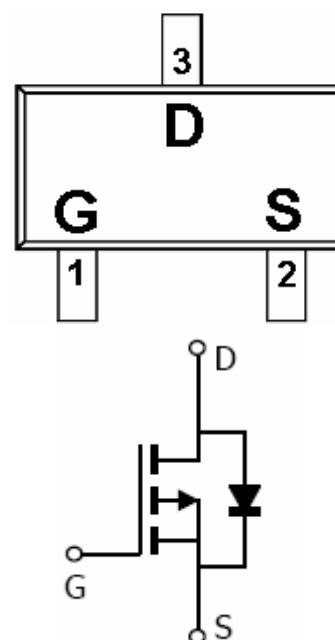
FEATURES

- ◆ -30V/-2.6A,RDS(ON)=130mΩ@VGS=-10V
- ◆ -30V/-2.0A,RDS(ON)=180mΩ@VGS=-4.5V
- ◆ Super high density cell design for extremely low Rds (ON)
- ◆ Exceptional on-resistance and maximum DC current capability
- ◆ SOT-23-3L package design

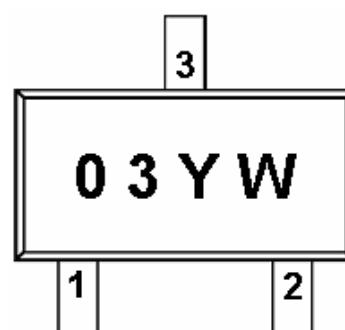
APPLICATIONS

- Power Management in Note book
- Portable Equipment
- Battery Powered System
- DC/DC Converter
- Load Switch
- DSC
- LCD Display inverter

PIN CONFIGURATION(SOT-23-3L)



PART MARKING



Y : Year Code
W : Week Code

SPP2303

PIN DESCRIPTION

Pin	Symbol	Description
1	G	Gate
2	S	Source
3	D	Drain

ORDERING INFORMATION

Part Number	Package	Part Marking
SPP2303S23RG	SOT-23-3L	03YW

※ Week Code : A ~ Z(1 ~ 26) ; a ~ z(27 ~ 52)

※ SPP2303S23RG : Tape Reel ; Pb – Free

ABSOULTE MAXIMUM RATINGS

(TA=25°C Unless otherwise noted)

Parameter	Symbol	Typical	Unit	
Drain-Source Voltage	V _{DSS}	-30	V	
Gate –Source Voltage	V _{GSS}	±20	V	
Continuous Drain Current(T _J =150°C)	T _A =25°C	ID	-3.0	A
	T _A =70°C		-2.0	
Pulsed Drain Current	I _{DM}	-10	A	
Continuous Source Current(Diode Conduction)	I _S	-1.25	A	
Power Dissipation	T _A =25°C	P _D	1.25	W
	T _A =70°C		0.8	
Operating Junction Temperature	T _J	150	°C	
Storage Temperature Range	T _{STG}	-55/150	°C	
Thermal Resistance-Junction to Ambient	R _{θJA}	100	°C/W	

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ELECTRICAL CHARACTERISTICS

(TA=25°C Unless otherwise noted)

Parameter	Symbol	Conditions	Min.	Typ	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} =0V, ID=-10uA	-30			V
Gate Threshold Voltage	V _{GS(th)}	V _D =V _G , ID=-250uA	-1.0		-3.0	
Gate Leakage Current	I _{GSS}	V _D =0V, V _G =±20V			±100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _D =-30V, V _G =0V			-1	uA
		V _D =-30V, V _G =0V T _J =55°C			-10	
On-State Drain Current	I _{D(on)}	V _D ≤-5V, V _G =-10V	-6			A
Drain-Source On-Resistance	R _{DSS(on)}	V _G =-10V, ID=-2.6A		0.095	0.130	Ω
		V _G =-4.5V, ID=-2.0A		0.125	0.180	
Forward Transconductance	g _f s	V _D =-10V, ID=-1.7A		2.4		S
Diode Forward Voltage	V _{SD}	I _S =-1.25A, V _G =0V		-0.8	-1.2	V
Dynamic						
Total Gate Charge	Q _g	V _D =-15V, V _G =-10V ID=-1.7A		5.8	10	nC
Gate-Source Charge	Q _{gs}			0.8		
Gate-Drain Charge	Q _{gd}			1.5		
Input Capacitance	C _{iss}	V _D =-15V, V _G =0V f=1MHz		226		pF
Output Capacitance	C _{oss}			87		
Reverse Transfer Capacitance	C _{rss}			19		
Turn-On Time	t _{d(on)}	V _D =-15V, R _L =15Ω ID=-1.0A, V _{GEN} =-10V R _G =6Ω		9	20	ns
	t _r			9	20	
Turn-Off Time	t _{d(off)}			18	35	
	t _f			6	20	